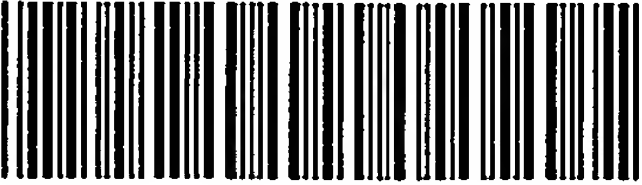


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/665,226	EHRlich, RICHARD M.	
	Examiner	Art Unit	
	Natalia Figueroa	2651	

SEARCHED			
Class	Subclass	Date	Examiner
360	65,48-49	3/24/2005	NFM
360	53,46	3/24/2005	NFM
360	67,57	3/24/2005	NFM2
360	77.08	3/24/2005	NFM
360	78.14	3/24/2005	NFM

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
EAST Search	3/23/2005	NFM
NPL Search (IEEE Database)	3/23/2005	NFM
NPL Search (JPO Database)	3/23/2005	NFM
Kin Wong	3/23/2005	NFM